

## **Large area CNT-Si heterojunction for photodetection**

**Carla Aramo for PARIDE Collaboration**



**Carla Aramo -**

# **Micro&Nano for photon detection**

### **MACRO MICRONANO**



## **from Vacuum to Silicon to Carbon**







## **Growth Mechanism of Carbon Nanotubes (CVD)**







Istituto Nazionale<br>di Fisica Nucleare

**INFN Napoli** *VCI Vienna, February 15-19, 2016* 

**Polycrystalline** 

shell



## **MWCNT photo absorbance**





## **Sapphire prototype detector**







The response of the MWCNT carpet to a monochromatic pulsed light, showing the highest and faster detection efficiency for the UV light. These characteristics make the **material highly interesting for UV photodetection.**



## **Main problems with sapphire photodetector**

- **1. High dark current between metallic electrodes;**
- **2. Low level of photocurrent (no signal amplification can be applied without amplifying the dark current also ).**





**Drain Voltage (V)** 

 **The use of a layered silicon substrate permits to collect the generated photocurrent through the silicon avoiding the surface dark current.**

**Solution: create <sup>a</sup> MWCNT-Si photosensitive heterojunction in which CNTs film converts photons into electrons and the layered silicon substrate amplify the signal by means of <sup>a</sup> secondary dicharge.**



# **The results of first MWCNT-Si device**





 $1,0$ 



 $(c)$ 

 $10 \mu m$ **Ni Catalyst deposition** 

**700°**

*Electrical analysis of carbon nanostructures/silicon heterojunctions designed for radiation detection***, NIM A 629, 377–381 (2011)**

*Innovative carbon nanotube – silicon large area photodetector***, 2012 JINST 7 P08013 2012.**



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X position (mm)

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The device substrate has the structure of a Metal-Insulator-Silicon (MIS) photodiode: applying an external electrical field between the two electrodes on the front and on the back of silicon layer and operating voltage sweeps the dark current assumes a straighten **behavior typical** of **a** diode.



## **Large area MWCNT-Si radiation detector**



**The application of voltage sweeps to the device generates the heterojunction between CNT and silicon substrate: the dark current measured between electrodes in the front and in the back of device assumes <sup>a</sup> threshold behavior.**



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**An electrical field can be applied between the two sides of device obtaining <sup>a</sup> large area photodiode whose equivalent circuit is depicted in figure, where <sup>D</sup> is the device, IL is the photocurrent generated by the incident light, Cj is the heterojunction** capacity,  $R_{sh}$  the shunt resistance and  $R_{sh}$ **the circuit resistance.**



**The heterojunction is characterized by <sup>a</sup> well defined threshold at 2.4 <sup>V</sup> completely absent in the substrate without CNTs. Dark current is about <sup>2</sup> nA for <sup>a</sup> surface of 0.5 cm<sup>2</sup>**

## **Photocurrent and linearity**

#### **0,400.40FBK\_Fe** 1.0 mW 1.0 mW $\blacksquare$ **FBK\_Ni0,350.35** 0.9 mW 0.9 mW 0.8 mW 0.8 mW**0,300.30** 0.7 mW 0.7 mWPhotocurrent (mA) **Photocurrent (mA) Photocurrent (mA)** Photocurrent (mA) **0,25** 0.6 mW**0.25** 0.6 mW 0.5 mW 0.5 mW**0.200,20** 0.4 mW 0.4 mW 0.3 mW**0.150,15** 0.3 mW 0.2 mW 0.2 mW**0.10** $\blacksquare$ **0,10** 0.1 mW 0.1 mW Dark**0.050,050.000,00-0.05-0,05<sup>0</sup> <sup>5</sup> <sup>10</sup> <sup>15</sup> <sup>20</sup> -10 -5 <sup>0</sup> <sup>5</sup> <sup>10</sup> <sup>15</sup> <sup>20</sup> <sup>25</sup> <sup>30</sup> Voltage (V)Voltage (V)1.2Room temperatureNo electronics1.0No signal amplification 0.8Long and stable plateau** Power (mW) **Power (mW) 0.6Linearity I vs P** 405 nm 532 nm**Threshold0.4** 650 nm**No saturation observed** 685 nm 808 nm**0.2Uniformity on all the CNT surface** 880 nm 980 nm**Long term stability (>8 years) 0.0Breakdrown @ >100 V**  $0.00$ **Photocurrent (mA)**

### **685 nm light emitting diode (LED) laser**





The quantum efficiency (QE) of the device was estimated as the ratio of the number of electrons collected at plateau (I) to the number of incident photons according to the relation:

$$
QE \pm \sigma_{QE} = \frac{hcI}{\lambda eP} \pm \frac{hc}{e} \sqrt{\left(\frac{1}{\lambda P}\right)^2 \sigma_I^2 + \left(\frac{I}{\lambda^2 P}\right)^2 \sigma_A^2 + \left(\frac{I}{P^2 \lambda}\right)^2 \sigma_P^2}
$$



**Quantum efficiency of CNTs with Ni catalyst appears much higher than that of CNTs with Fe catalyst, especially in the UV and IR regions.** 



## **Tunnel effect**



**The shape of the current-voltage curve presents <sup>a</sup> negative differential resistance and resembles that of <sup>a</sup> resonant tunneling junction.**

**These observations clearly indicate that impinging light and, as <sup>a</sup> consequence, the photogenerated charges play <sup>a</sup> fundamental role in the heterojunction behaviour.**

**The current shape similarity with that of typical resonant tunneling junction suggests that <sup>a</sup> kind of electronic resonance process induced by the photogenerated charges may be present.**

**Resonant tunnel-like current is generated only under light radiation and it is function of the wavelength as well as of the power intensity**

# **Study of heterojunction MWCNT-Si**



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### Electrical analysis of carbon nanostructures/silicon heterojunctions designed for radiation detection

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#### ABSTRACT

A new class of fadiation detectors based on carbon nanostructures as the active photosensitive elemes been recently developed. In this scenario the optimization of the device, both in dark and on light irradiation, is a crucial point. Here, we report on electrical measurements performed in dark conditions on carbon nanofibers and nanotubes deposited on silicon substrates. Our experimental results were interpreted in terms of a multistep tunneling process occurring at the carbon nanostructures/silicon interface

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# Key point → how the hetero-junction creates?



**The presence of the insulator is bypassed by the formation of permanent low resistivity conduction channels which are created as an external voltage is applied to the device thanks to the peculiar characteristics of the nanotubes to appear as unidimensional elements.** 



**The C-V plot indicates the change of capacitance at the same voltage threshold of 2.4 V. The MWCNTs act as <sup>a</sup> semi-metallic layer, the silicon substrate is ndoped and the nitrite layer is the pierced insulating dielectric.**



## **Phototransistor-like device configuration**



**Depletion regions amplitude depends on the applied voltage. The silicon** bulk, 625  $\mu$ m thick, can be considered as a passive resistance except in the **depletion areas.**

The MIS depletion area cannot be reached from optical radiation because of **the presence of metal.**

**Instead the depletion area created by the CNT-Si heterojunction can be** reached and activated by the radiation due to the nanotube characteristics. A **light's fraction is absorbed inside CNT and converted in hole-electron pairs or excitons. The other reaches silicon and is converted inside.**

**The described device can be considered as a "phototransistor"**





## **Key points of a CNT-Si photodetector**

![](_page_20_Figure_1.jpeg)

- **1. A large area photodetector build by simply growing CNTs on a n-type silicon substrate;**
- **2. <sup>a</sup> CNT-Si heterojunction is created applying voltage sweeps to the electrodes;**
- **3. the device presents a great uniformity over all the sensitive area;**
- **4. QE and photoresponsivity are comparable to that of commercial photodiode;**
- 5. charge collected presents a great linearity and saturation effects have been observed;
- **6. photosensistivity extends in a wide wavelength range, from UV to IR;**
- **7. the device can be used both to detect continuous and pulses light;**
- **8. at present no amplification – can detect light pulses with large number of photons (>104)**

![](_page_20_Picture_10.jpeg)

![](_page_21_Figure_0.jpeg)

![](_page_22_Figure_0.jpeg)

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## **Signal vs drain voltage @ 81nJ**

![](_page_23_Figure_1.jpeg)

**The signal shape strongly depends from the CNT catalyst and from the laser light intensity, less from the drain voltage applied.** 

**The incident radiation excites CNTs energetic levels and the drain voltage collects the generated charge. No saturation effects have been observed.** 

![](_page_23_Picture_4.jpeg)

![](_page_24_Figure_0.jpeg)

- The MWCNTs with Ni catalyst shows an higher charge generation than Fe.
- In spite of the high light intensity the photodetector charge is linear for all **drain voltage range and not in saturation.**
- **The charge distributions are well separeted for all drain voltage range.**

![](_page_24_Picture_4.jpeg)

![](_page_25_Figure_0.jpeg)

![](_page_26_Picture_0.jpeg)

# SiPM\_CNT Project

• SiPMs based on FBK NUV-HD technology and specifically designed for CNT

6 mm

*Typical specs of the standard NUV-HD SiPMs*

![](_page_26_Picture_140.jpeg)

![](_page_26_Figure_5.jpeg)

*SEM Image of the single cell composing the SiPM (cell size = 25um)*

![](_page_26_Figure_7.jpeg)

**AND IMAGE SENSOR** 

![](_page_27_Figure_0.jpeg)

**AND IMAGE SENSORS** 

## **Main Scientific Challenges**

 **Increase quantum efficiency due to the photoresponsivity enhancement from MWCNT absorbance, in the wavelengthrange 200-400 nm.**

sample A sample E  $T = 750 C<sup>o</sup>$  $^{\circ}$  $0.6$  $0.4$ 

- **Decrease dark noise thanks to heterojunction MWCNT/Si** - **increase the device area (cm<sup>2</sup> or more VS mm<sup>2</sup> SiPM).**
- **MWCNT** bottom-up technology  $\rightarrow$  cells (pad<br>or strip) bundreds of nm up to mm VS 15 um **or strip) hundreds of nm up to mm VS <sup>15</sup>** <sup>µ</sup>**<sup>m</sup>up to <sup>100</sup>** <sup>µ</sup>**<sup>m</sup> for SiPM.**

![](_page_28_Figure_5.jpeg)

![](_page_28_Figure_6.jpeg)

 $\checkmark$  **Maximizes the sensitive area for photoconversion and its uniformity** - **Electric field applied via <sup>a</sup> conductive coating.**

![](_page_28_Picture_8.jpeg)

![](_page_28_Picture_9.jpeg)

## **Light absorption**

![](_page_29_Figure_1.jpeg)

**The CNT layer absorbs UV photons producing photoelectrons that can be transferred by means of an external electrical field inside the depletion zone of the hetero-junction. Therefore the charge induces <sup>a</sup> photocurrent drained out by the applied voltage.**

![](_page_29_Picture_3.jpeg)

![](_page_30_Figure_0.jpeg)

![](_page_30_Picture_1.jpeg)

**Nano-pixelled photocathodes sensitive to the UV radiation may be obtained by means of nanolithography in a very cheap and easy way!**

EHT = 10.00 KV  $MD = R$ 

![](_page_30_Picture_4.jpeg)

![](_page_30_Picture_5.jpeg)

![](_page_31_Figure_0.jpeg)

## **Building nano - detecting micro**

![](_page_31_Picture_2.jpeg)

![](_page_32_Picture_0.jpeg)

## **INFN**

![](_page_33_Figure_0.jpeg)

![](_page_34_Figure_0.jpeg)

![](_page_34_Figure_1.jpeg)

 $1.5$ 

 $d$  (nm)

 $2.0$ 

 $0.4$ 

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 $10$ 

## CNT energetic levels

**Semiconductors nanotubes show interesting fluorescence properties in the region of close infrared** (from  $\sim$  1 to  $\sim$  15  $\mu$ m) tied to their electronic **characteristics.** *Nanotubes of type n-m=3p with p entire positive or null are metallic conductors***.** 

**All the others are semiconductors whose gap is function of the diameter, and are approximated from the function:** 

$$
E_{\text{gap}}=2 y_0 \text{acc/d}
$$

where  $y_0$ =0.1 eV, acc=0.142 nm and d is the diameter. **This implies that for the Single Wall CNT the fundamental gap varies from 0.4 to 0.7 eV.** 

**Multi Wall CNT instead present a wider range of energy gap.**

![](_page_35_Figure_0.jpeg)

**R. Saito, G. Dresselhaus and M.S. Dresselhaus,** *Physical Properties of Carbon Nanotubes***, Imperial College Press (2003)**

![](_page_35_Picture_2.jpeg)

 $\pi/a$ 

![](_page_36_Picture_0.jpeg)

![](_page_36_Picture_1.jpeg)

### **Great uniformity over large area**

![](_page_37_Figure_1.jpeg)

**The electric field applied uniformly over the entire CNT surface plays <sup>a</sup> fundamental making uniform the charge electrodes.**

**The signal generated everywhere in the sample can be collected to the metallic electrodes through the ITO layer, whose resistivity is very low.**

![](_page_37_Picture_4.jpeg)

## **Si-CNT photodetector responsivity**

![](_page_38_Figure_1.jpeg)

### **Responsivity comparison between Si-CNT prototype and commercial photodiode**

![](_page_38_Picture_3.jpeg)

## **Si-CNT photoresponsivity**

![](_page_39_Figure_1.jpeg)

**<sup>A</sup> particular layered substrate without the schottky junction on the back shows very peculiar characteristics: high quantum efficency in all the wide wavelength range, <sup>a</sup> hetero-junction threshold at 2.5 <sup>V</sup> and <sup>a</sup> well** defined tunnel effect under this voltage. Work on this substrate is still in **progress.**

![](_page_39_Picture_3.jpeg)